



## P-Channel Rated MOSFET + Schottky Diode

### Characteristics

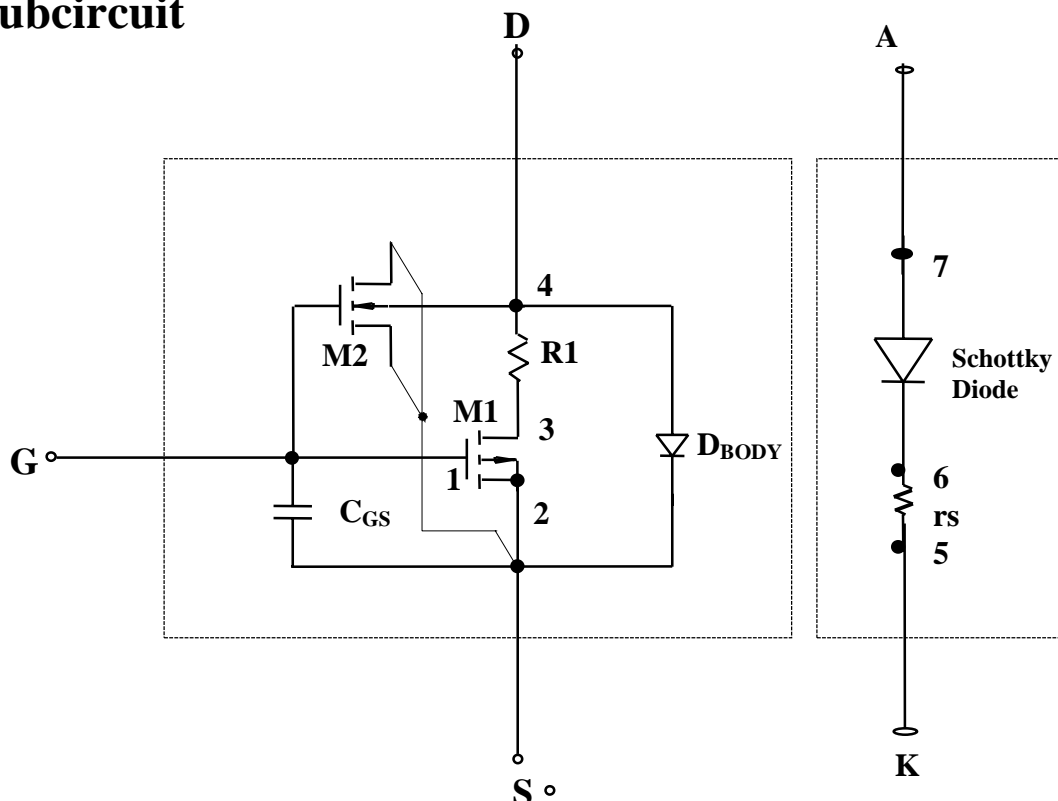
- P-Channel Vertical DMOS
- Macro-Model (Subcircuit)
- Level 3 MOS
- Applicable for Both Linear and Switch Modes
- Applicable Over a -55 to 125 ° C Temperature Range
- Models Gate Charge, Transient and Diode Reverse Recovery Characteristics

### Description

The attached SPICE model describes typical electrical characteristics of the Si6923DQ p-channel vertical trench-gated DMOS and the Schottky Diode. The subcircuit model was extracted and optimized over a 25 ° C to 125 ° C temperature range under pulse conditions for 0 to 5 volt gate drives. Saturated output impedance model accuracy has been maximized for gate biases near

threshold. A novel gate-to-drain feedback capacitance network is used to model gate charge characteristics while avoiding convergence problems of switched Cgd models. Model parameters values are optimized to provide a best fit to measured electrical data and are not intended as an exact physical description of a device.

### Model Subcircuit



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designer should refer to the appropriate data sheet of the same number for guaranteed specification limits.



# SPICE Device Model Si6923DQ

## P-Channel Device ( $T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Conditions	Typ	Unit
<b>Static</b>				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.898	V
On-State Drain Current <sup>a</sup>	$I_{D(on)}$	$V_{DS} = -5\text{ V}, V_{GS} = -4.5\text{ V}$	74.3	A
Drain-Source On-State Resistance <sup>a</sup>	$r_{DS(on)}$	$V_{GS} = -4.5\text{ V}, I_D = -3.5\text{ A}$	0.0375	$\Omega$
		$V_{GS} = -2.5\text{ V}, I_D = -2.7\text{ A}$	0.0572	
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = -10\text{ V}, I_D = -3.5\text{ A}$	11.5	S
Forward Voltage <sup>a</sup>	$V_{SD}$	$I_F = I_S = -1.25\text{ A}, V_{GS} = 0\text{V}$	0.815	V
<b>Dynamic</b>				
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{ V}, V_{DS} = -10\text{ V}, f = 1\text{MHz}$	1950	pF
Output Capacitance	$C_{oss}$		316	
Reverse Transfer Capacitance	$C_{rss}$		128	
Total Gate Charge <sup>b</sup>	$Q_g$	$V_{DS} = -10\text{ V}, V_{GS} = -4.5\text{ V}$ $I_D = -3.2\text{ A}$	13.3	nC
Gate-Source Charge <sup>b</sup>	$Q_{gs}$		2.8	
Gate-Drain Charge <sup>b</sup>	$Q_{gd}$		2.9	
Turn-On Delay Time <sup>b</sup>	$t_{d(on)}$	$V_{DD} = -10\text{ V}, R_L = 10\ \Omega$ $I_D \cong -1\text{ A}, V_{GEN} = -4.5\text{ V},$ $R_G = 6\ \Omega$	14.8	ns
Rise Time <sup>b</sup>	$t_r$		13.8	
Turn-Off Delay Time <sup>b</sup>	$t_{d(off)}$		61.8	
Fall Time <sup>b</sup>	$t_f$		16.2	
<b>Schottky Diode</b>				
Forward Voltage Drop	$V_f$	$I_F = 1\text{A}$	0.45	V
Junction Capacitance	$C_T$	$V_R = 10\text{ v}$	60	pf

Notes:

a. Pulse test: Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$

b. Independent of operating temperature.

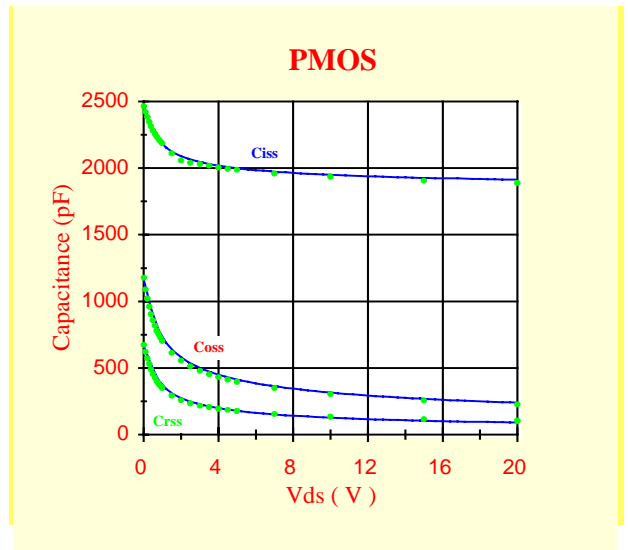
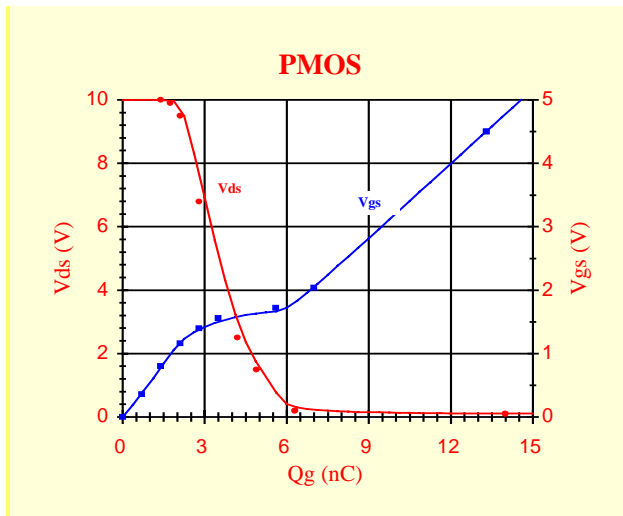
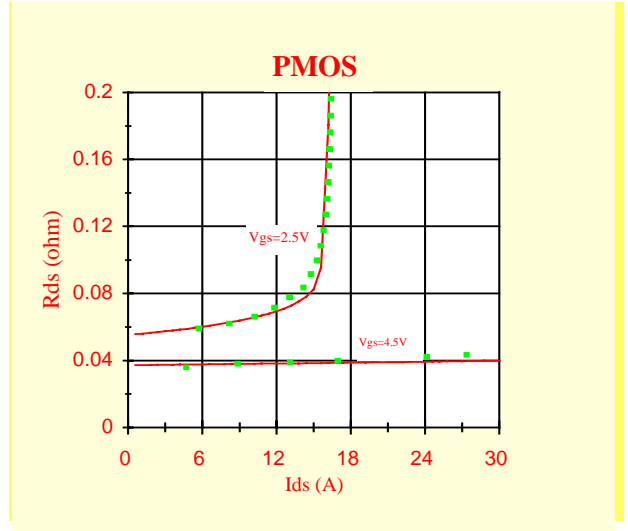
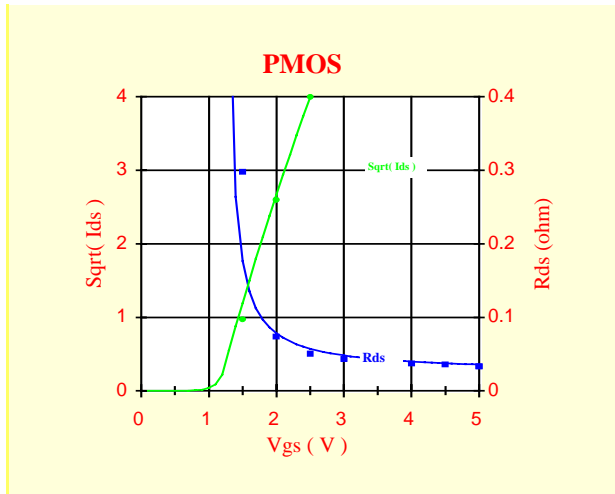
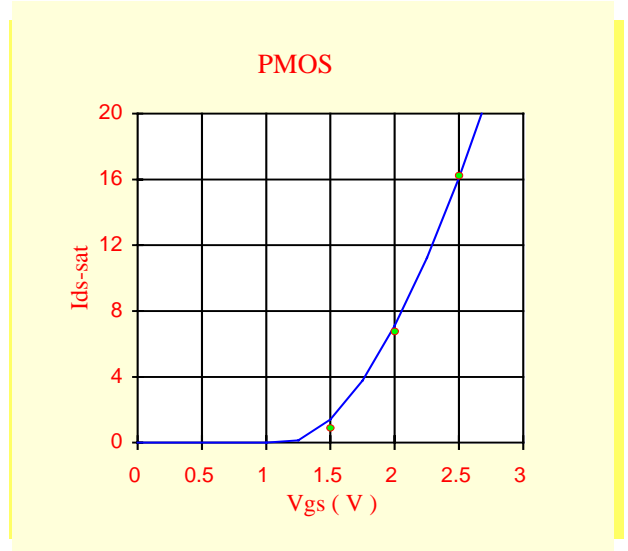
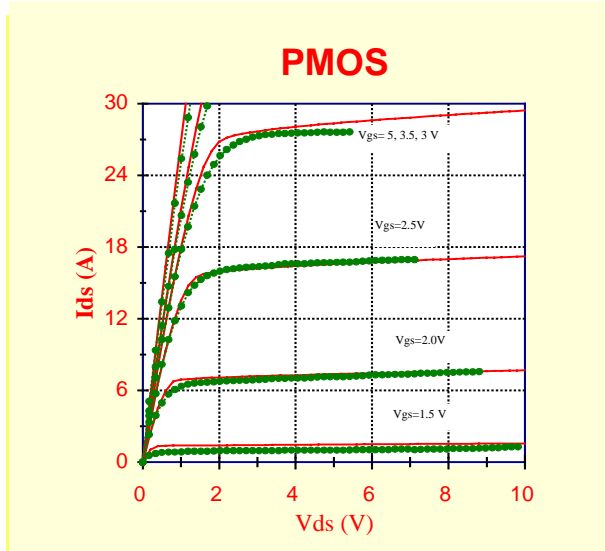


# SPICE Device Model Si6923DQ



# SPICE Device Model Si6923DQ

Comparison of Model with Measured Data





# SPICE Device Model Si6923DQ

Comparison of Model with Measured Data

( $T_j =$

